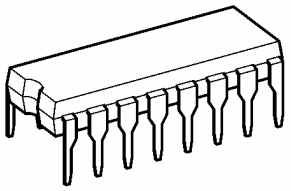
TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74AC109P,TC74AC109F,TC74AC109FN

Dual J-K Flip Flop with Preset and Clear

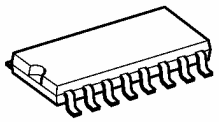
Note: xxxFN (JEDEC SOP) is not available in Japan.

TC74AC109P



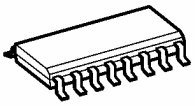
DIP16-P-300-2.54A

TC74AC109F



SOP16-P-300-1.27A

TC74AC109FN



SOL16-P-150-1.27

Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

The TC74AC109 is an advanced high speed CMOS DUAL J-$\overline{K}$ FLIP FLOP fabricated with silicon gate and double-layer metal wiring C^2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

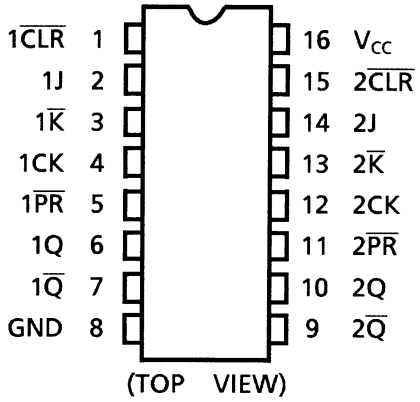
In accordance with the logic level given J and $\overline{K}$ input this device changes state on positive going transition of the clock pulse. $\overline{CLEAR}$ and $\overline{PRESET}$ are independent of the clock and accomplished by a low logic level on the corresponding input.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

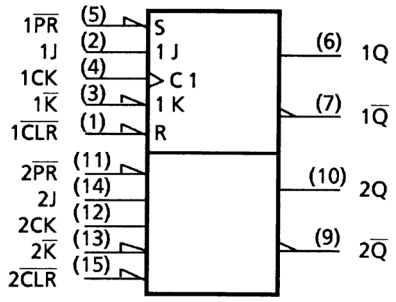
Features

- High speed: f_{max} = 200 MHz (typ.) at V_{CC} = 5 V
- Low power dissipation: I_{CC} = 4 μA (max) at Ta = 25°C
- High noise immunity: $V_{NIH} = V_{NIL}$ = 28% V_{CC} (min)
- Symmetrical output impedance: $|I_{OH}| = I_{OL}$ = 24 mA (min)
  Capability of driving 50 Ω transmission lines.
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2 to 5.5 V
- Pin and function compatible with 74F109

Pin Assignment



IEC Logic Symbol

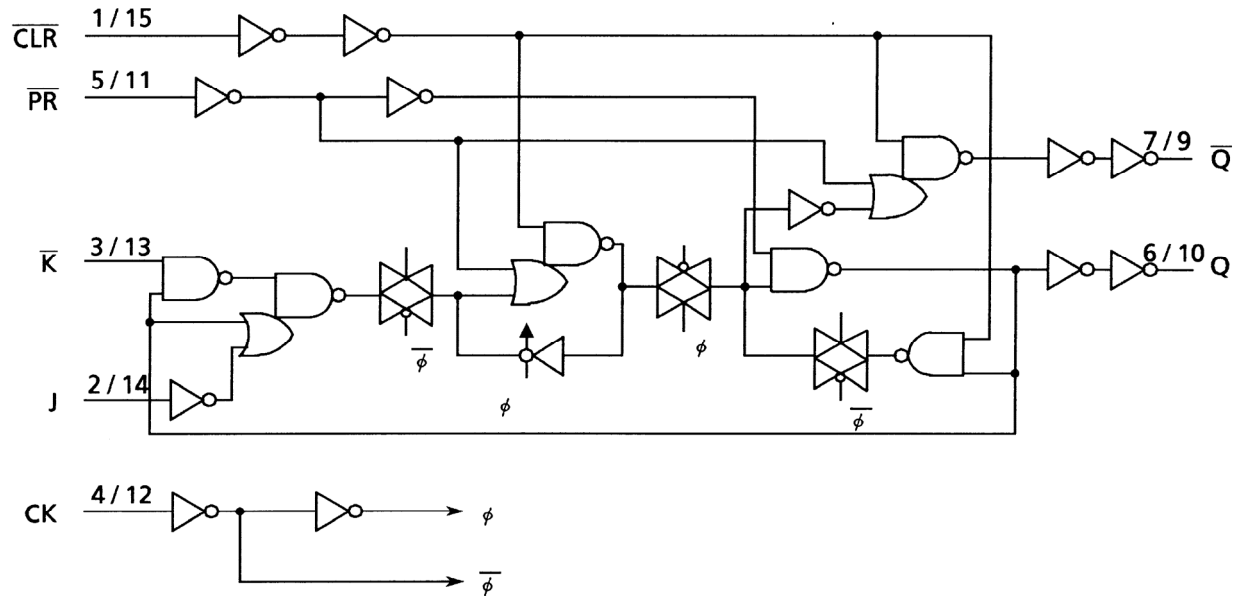


Truth Table

Inputs					Outputs		Function
$\overline{CLR}$	$\overline{PR}$	J	$\overline{K}$	CK	Q	$\overline{Q}$	
L	H	X	X	X	L	H	Clear
H	L	X	X	X	H	L	Preset
L	L	X	X	X	H	H	
H	H	L	H	↑	Q_n	$\overline{Q}_n$	No Change
H	H	L	L	↑	L	H	
H	H	H	H	↑	H	L	
H	H	H	L	↑	$\overline{Q}_n$	Q_n	Toggle
H	H	X	X	↓	Q_n	$\overline{Q}_n$	No Change

X: Don't care

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	−0.5 to 7.0	V
DC input voltage	V_{IN}	−0.5 to V_{CC} + 0.5	V
DC output voltage	V_{OUT}	−0.5 to V_{CC} + 0.5	V
Input diode current	I_{IK}	±20	mA
Output diode current	I_{OK}	±50	mA
DC output current	I_{OUT}	±50	mA
DC V_{CC}/ground current	I_{CC}	±100	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = −40 to 65°C. From Ta = 65 to 85°C a derating factor of −10 mW/°C should be applied up to 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0 to 5.5	V
Input voltage	V_{IN}	0 to V_{CC}	V
Output voltage	V_{OUT}	0 to V_{CC}	V
Operating temperature	T_{opr}	−40 to 85	°C
Input rise and fall time	dt/dV	0 to 100 (V_{CC} = 3.3 ± 0.3 V) 0 to 20 (V_{CC} = 5 ± 0.5 V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		V_{CC} (V)	Ta = 25°C Min	Ta = 25°C Typ.	Ta = 25°C Max	Ta = −40 to 85°C Min	Ta = −40 to 85°C Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	—	1.50	—	V
				3.0	2.10	—	—	2.10	—	
				5.5	3.85	—	—	3.85	—	
Low-level input voltage	V_{IL}	—		2.0	—	—	0.50	—	0.50	V
				3.0	—	—	0.90	—	0.90	
				5.5	—	—	1.65	—	1.65	
High-level output voltage	V_{OH}	V_{IN} = V_{IH} or V_{IL}	I_{OH} = −50 μA	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
				4.5	4.4	4.5	—	4.4	—	
			I_{OH} = −4 mA	3.0	2.58	—	—	2.48	—	
			I_{OH} = −24 mA	4.5	3.94	—	—	3.80	—	
			I_{OH} = −75 mA (Note)	5.5	—	—	—	3.85	—	
Low-level output voltage	V_{OL}	V_{IN} = V_{IH} or V_{IL}	I_{OL} = 50 μA	2.0	—	0.0	0.1	—	0.1	V
				3.0	—	0.0	0.1	—	0.1	
				4.5	—	0.0	0.1	—	0.1	
			I_{OL} = 12 mA	3.0	—	—	0.36	—	0.44	
			I_{OL} = 24 mA	4.5	—	—	0.36	—	0.44	
			I_{OL} = 75 mA (Note)	5.5	—	—	—	—	1.65	
Input leakage current	I_{IN}	V_{IN} = V_{CC} or GND		5.5	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I_{CC}	V_{IN} = V_{CC} or GND		5.5	—	—	4.0	—	40.0	μA

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

Timing Requirements (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C	Ta = −40 to 85°C	Unit
			V_{CC} (V)	Limit	Limit	
Minimum pulse width (CK)	$t_{W(L)}$ $t_{W(H)}$	—	3.3 ± 0.3 5.0 ± 0.5	8.0 5.0	8.0 5.0	ns
Minimum pulse width ($\overline{CLR}$, $\overline{PR}$)	$t_{W(L)}$	—	3.3 ± 0.3 5.0 ± 0.5	7.0 5.0	7.0 5.0	ns
Minimum set-up time	t_s	—	3.3 ± 0.3 5.0 ± 0.5	9.0 5.0	9.0 5.0	ns
Minimum hold time	t_h	—	3.3 ± 0.3 5.0 ± 0.5	0.0 0.0	0.0 0.0	ns
Minimum removal time ($\overline{CLR}$, $\overline{PR}$)	t_{rem}	—	3.3 ± 0.3 5.0 ± 0.5	3.0 2.0	3.0 2.0	ns

AC Characteristics ($C_L = 50$ pF, $R_L = 500\ \Omega$, input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40 to 85°C		Unit
			V_{CC} (V)	Min	Typ.	Max	Min	Max	
Propagation delay time (CK-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	8.2 6.1	13.9 8.7	1.0 1.0	16.0 10.0	ns
Propagation delay time ($\overline{CLR}$, $\overline{PR}$-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	3.3 ± 0.3 5.0 ± 0.5	— —	8.5 6.4	14.4 9.1	1.0 1.0	16.6 10.5	ns
Maximum clock frequency	f_{max}	—	3.3 ± 0.3 5.0 ± 0.5	55 100	120 160	— —	55 100	— —	MHz
Input capacitance	C_{IN}	—		—	5	10	—	10	pF
Power dissipation capacitance	C_{PD} (Note)	—		—	82	—	—	—	pF

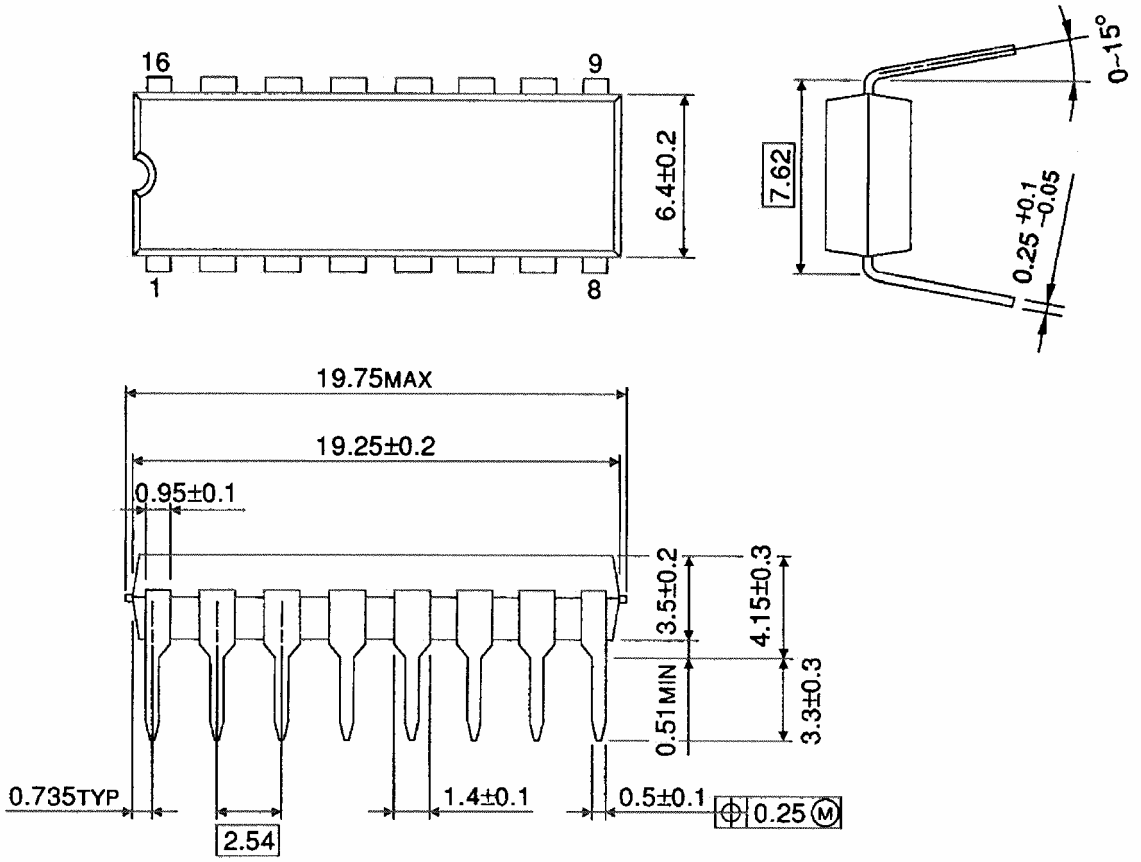
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}\ (opr) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2\ (per\ F/F)$$

Package Dimensions

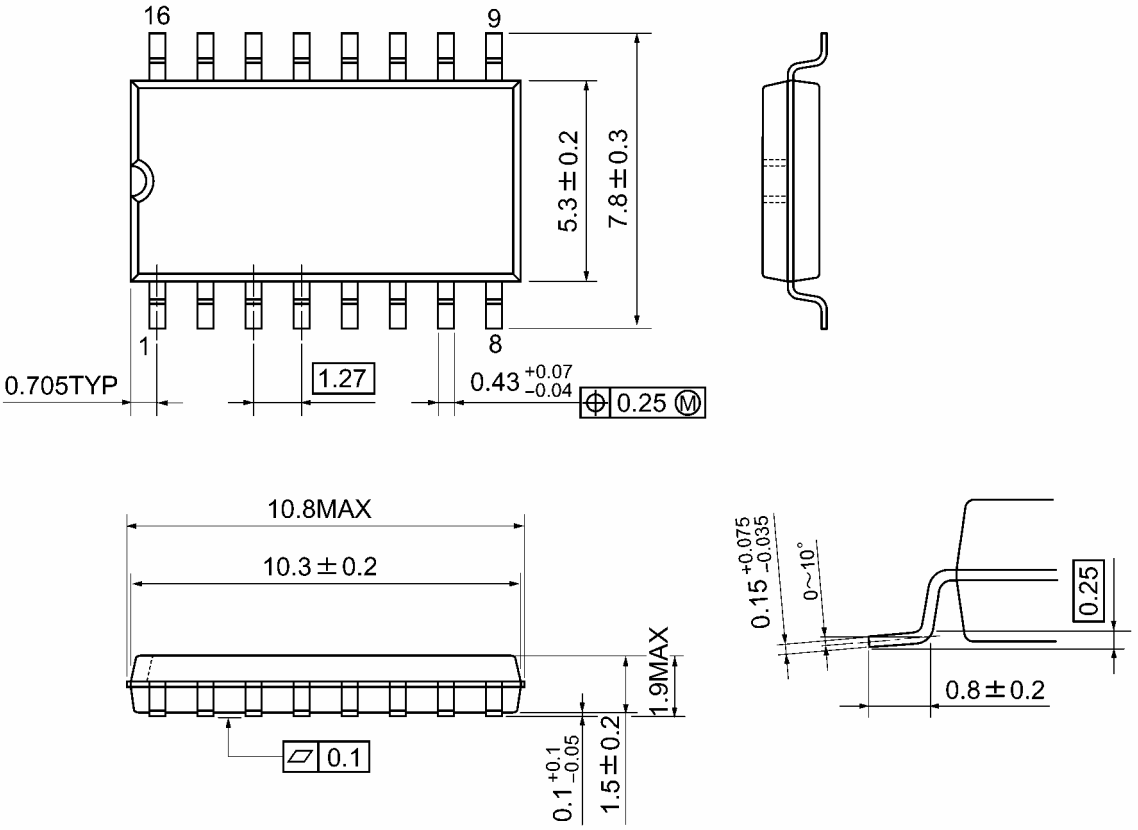
DIP16-P-300-2.54A Unit : mm



Weight: 1.00 g (typ.)

Package Dimensions

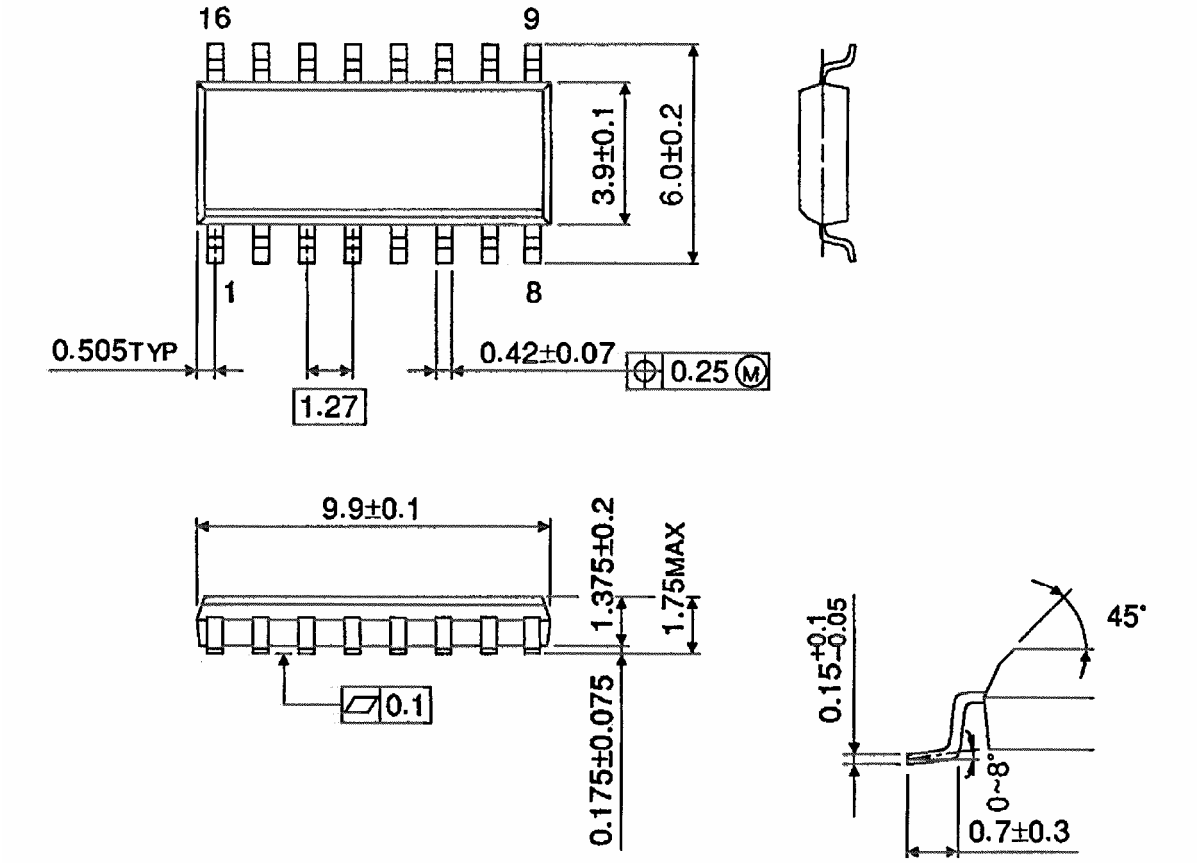
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27 Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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